

Date Mailed: April 15, 2003

Sheet 1 of 2

FORM 1449

INFORMATION DISCLOSURE STATEMENT

IN AN APPLICATION

(Use several sheets if necessary)

Docket Number:
10873.792USD1

Application Number:

10/848,742

Applicant: HIRAMOTO et al.

Filing Date: August 14, 2004

Group Art Unit: 1775

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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						YES	NO
KB	0,913 830	05.1999	EP				
KB	1 033 764	09.2000	EP				
KB	199 34 009	01.2000	DE				SEE IDS

EXAMINER

/Kevin Bernatz/

DATE CONSIDERED 10/23/2006

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.

*Substitute Disclosure Statement Form (PTO-1449)

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Sheet 2 of 2

FORM 1449* INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION (Use several sheets if necessary)	Docket Number: 10873.792USD1	Application Number: 097348 10/848,742
	Applicant: HIRAMOTO et al.	
	Filing Date: August 16, 2001	Group Art Unit: 1775

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EXAMINER	/Kevin Bernatz/	DATE CONSIDERED	10/23/2006
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